

SEMITOP[®] 2

IGBT Module

SK30GB128

SK30GAL128

SK30GAR128

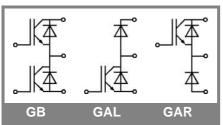
Preliminary Data

Features

- Compact design
- One screw mounting
- Heat transfer and isolation through direct copper bonded aluminium oxide ceramic (DCB
- High short circuit capabilitySPT= Soft Punch Through
- SPT= Soft Punch Through technology
- V_{ce,sat} with positive coefficient

Typical Applications

- Switching (not for linear use)
- Inverter
- Switched mode power supplies
- UPS



| Absolute Maximum Ratings T _s = 25 °C, unless otherwise specifie | | | | |
|--|---|---------------------------|----------|-------|
| Symbol | Conditions | | Values | Units |
| IGBT | | | | |
| V _{CES} | T _j = 25 °C T _i = 125 °C | | 1200 | V |
| I _C | T _j = 125 °C | T _s = 25 °C | 35 | А |
| | | T _s = 80 °C | 25 | А |
| I _{CRM} | I _{CRM} = 2 x I _{Cnom} | | 50 | А |
| V _{GES} | | | ± 20 | V |
| t _{psc} | V_{CC} = 600 V; $V_{GE} \le 20$ V; VCES < 1200 V | T _j = 125 °C | 10 | μs |
| Inverse D | | | · | |
| I _F | T _j = 150 °C | T _s = 25 °C | 37 | А |
| | | T _s = 80 °C | 25 | А |
| I _{FRM} | I _{FRM} = 2 x I _{Fnom} | | | А |
| I _{FSM} | t _p = 10 ms; half sine wave | T _j = 150 °C | 350 | А |
| Freewhee | eling Diode | | | |
| I _F | T _j = 150 °C | T _{case} = 25 °C | 37 | А |
| | | T _{case} = 80 °C | 25 | А |
| I _{FRM} | | | | А |
| I _{FSM} | t _p = 10 ms; half sine wave | T _j = 150 °C | 350 | А |
| Module | | | | |
| I _{t(RMS)} | | | | А |
| T _{vj} | | | -40 +150 | °C |
| T _{stg} | | | -40 +125 | °C |
| V _{isol} | AC, 1 min. | | 2500 | V |

| Characteristics | | T _s = | $_{\rm s}$ = 25 °C, unless otherwise specified | | | | |
|----------------------|--|---|--|------|------|-------|--|
| Symbol | Conditions | | min. | typ. | max. | Units | |
| IGBT | | | | | | | |
| V _{GE(th)} | $V_{GE} = V_{CE}, I_C = 1 \text{ mA}$ | | 4,5 | 5,5 | 6,5 | V | |
| I _{CES} | V_{GE} = 0 V, V_{CE} = V_{CES} | T _j = 25 °C | | 0,1 | 0,1 | mA | |
| | | T _j = 125 °C | | | | mA | |
| I _{GES} | V _{CE} = 0 V, V _{GE} = 20 V | T _j = 25 °C | | | 200 | nA | |
| | | T _j = 125 °C | | | | nA | |
| V _{CE0} | | T _j = 25 °C | | 1,1 | | V | |
| | | T _j = 125 °C | | 1 | | V | |
| r _{CE} | V _{GE} = 15 V | T _j = 25°C | | 36 | | mΩ | |
| | | T _j = 125°C | | 48 | | mΩ | |
| V _{CE(sat)} | I _{Cnom} = 25 A, V _{GE} = 15 V | T _j = 25°C _{chiplev.} | 1,7 | 2 | 2,3 | V | |
| . , | | T _j = 125°C _{chiplev} . | | 2,2 | 3,7 | V | |
| C _{ies} | | | | 1,9 | | nF | |
| C _{oes} | V_{CE} = 25, V_{GE} = 0 V | f = 1 MHz | | 0,16 | | nF | |
| C _{res} | | | | 0,09 | | nF | |
| t _{d(on)} | | | | 55 | | ns | |
| t _r | R _{Gon} = 15 Ω | V _{CC} = 600V | | 26 | | ns | |
| E _{on} | D (5.0 | I _{Cnom} = 30A | | 2,8 | | mJ | |
| t _{d(off)} | R_{Goff} = 15 Ω | $T_{j} = 125 \ ^{\circ}C$ | | 284 | | ns | |
| t _f | | V _{GE} =±15V | | 40 | | ns | |
| E _{off} | | | | 2,19 | | mJ | |
| $R_{th(j-s)}$ | per IGBT | | | | 1 | K/W | |



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| Symbol | Conditions | I | min. | typ | max. | Units |
|-----------------------|-----------------------------------|---|------|------|------|-------|
| - | | | | typ. | max. | Units |
| Inverse D | | T 05 00 | | • | 0.5 | |
| $V_F = V_{EC}$ | I_{Fnom} = 25 A; V_{GE} = 0 V | | | 2 | 2,5 | V |
| | | T _j = 125 °C _{chiplev.} | | 1,8 | 2,3 | V |
| V _{F0} | | T _j = 125 °C | | 1 | 1,2 | V |
| r _F | | T _j = 125 °C | | 32 | 44 | mΩ |
| I _{RRM} | I _{Fnom} = 22 A | T _i = 125 °C | | 25 | | А |
| Q _{rr} | di/dt = -500 A/µs | , | | 4,5 | | μC |
| E _{rr} | V _{CC} = 600V | | | 1 | | mJ |
| R _{th(j-s)D} | per diode | | | | 1,2 | K/W |
| | eling Diode | | | | | |
| $V_{F} = V_{EC}$ | | T _i = 25 °C _{chiplev.} | | 2 | 2,5 | V |
| | | T _j = 125 °C _{chiplev.} | | 1,8 | 2,3 | V |
| V _{F0} | | T _j = 125 °C | | 1 | 1,2 | V |
| r _F | | T _j = 125 °C | | 32 | 44 | V |
| I _{RRM} | I _{Fnom} = 22 A | T _i = 125 °C | | 253 | | Α |
| Q _{rr} | di/dt = -500 A/µs | , | | 4,5 | | μC |
| E _{rr} | V _R =600V | | | 1 | | mJ |
| | per diode | | | | 1,2 | K/W |
| M _s | to heat sink M1 | | | | 2 | Nm |
| w | | | | 19 | | g |

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

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